

Notice of References Cited

Application/Control No.

09/546,247

Applicant(s)/Patent Under

Reexamination

VAN LIEW ET AL.

Examiner

David L Jones

Art Unit

2622

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,646,764	11-2003	Wataya, Masafumi	358/3.28
	B	US-5,539,539	07-1996	Fujimoto et al.	358/518
	C	US-5,257,119	10-1993	Funada et al.	358/438
	D	US-6,044,182	03-2000	Daly et al.	382/284
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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